## Performance of plane wavefront Fizeau interferometers in power spectral density measurements with tilted plane optics (Erratum)

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Proceedings Volume 13150, Advances in X-Ray/EUV Optics and Components XIX; 1315006 (2024) <a href="https://doi.org/10.1117/12.3028336">https://doi.org/10.1117/12.3028336</a>

Event: Optical Engineering + Applications, 2024, San Diego, California, United States

Online Publication Date: 4 October 2024 Erratum Published: 7 January 2025

**Publisher's note**: this paper was originally published on 4 October 2024. A revised version was published on 7 January 2025. The original paper has been updated. Incorrect graphs have been replaced.

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